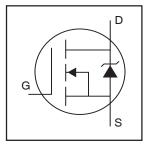
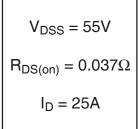
# International Rectifier

## IRLR3105PbF IRLU3105PbF HEXFET® Power MOSFET

#### **Features**

- Logic-Level Gate Drive
- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Timax
- Lead-Free

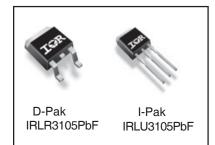




## **Description**

This HEXFET<sup>®</sup> Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in a wide variety of applications.

The D-Pak is designed for surface mounting using vapor phase, infrared, or wave soldering techniques. The straight lead version (IRLU series) is for through-hole mounting applications. Power dissipation levels up to 1.5 watts are possible in typical surface mount applications.



### **Absolute Maximum Ratings**

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	25	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	18	A
I <sub>DM</sub>	Pulsed Drain Current ①	100	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation	57	W
	Linear Derating Factor	0.38	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 16	V
E <sub>AS</sub>	Single Pulse Avalanche Energy@	61	mJ
E <sub>AS</sub> (tested)	Single Pulse Avalanche Energy Tested Value 7	94	
I <sub>AR</sub>	Avalanche Current①	See Fig.12a, 12b, 15, 16	A
E <sub>AR</sub>	Repetitive Avalanche Energy®		mJ
dv/dt	Peak Diode Recovery dv/dt ③	3.4	V/ns
TJ	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )	

### **Thermal Resistance**

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		2.65	
$R_{\theta JA}$	Junction-to-Ambient (PCB mount)*		50	°C/W
$R_{\theta JA}$	Junction-to-Ambient		110	

## IRLR/U3105PbF



## Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	55			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.056		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
Б	Oletia Beria la Oceana Oce Beriala de		30	37	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 15A ④
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		35	43	11152	V <sub>GS</sub> = 5.0V, I <sub>D</sub> = 13A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	1.0		3.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
g <sub>fs</sub>	Forward Transconductance	15			S	V <sub>DS</sub> = 25V, I <sub>D</sub> = 15A⊕
	Drain to Course Leakage Current			20	μA	$V_{DS} = 55V, V_{GS} = 0V$
I <sub>DSS</sub>	Drain-to-Source Leakage Current			250	μΛ	$V_{DS} = 44V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
	Gate-to-Source Forward Leakage			200	nA	V <sub>GS</sub> = 16V
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			-200	nA	V <sub>GS</sub> = -16V
Qg	Total Gate Charge			20		I <sub>D</sub> = 15A
Q <sub>gs</sub>	Gate-to-Source Charge			5.6	nC	$V_{DS} = 44V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge			9.0		$V_{GS} = 5.0V$ , See Fig. 6 and 13
t <sub>d(on)</sub>	Turn-On Delay Time		8.0			V <sub>DD</sub> = 28V
t <sub>r</sub>	Rise Time		57		1	I <sub>D</sub> = 15A
t <sub>d(off)</sub>	Turn-Off Delay Time		25			$R_G = 24\Omega$
tf	Fall Time		37			V <sub>GS</sub> = 5.0V, See Fig. 10 ④
L <sub>D</sub>	Internal Drain Inductance		4.5			Between lead,
					nH	6mm (0.25in.)
L <sub>S</sub>	Internal Source Inductance®		7.5			from package and center of die contact
C <sub>iss</sub>	Input Capacitance		710			V <sub>GS</sub> = 0V
Coss	Output Capacitance		150		1	$V_{DS} = 25V$
C <sub>rss</sub>	Reverse Transfer Capacitance		28		pF	f = 1.0MHz, See Fig. 5
Coss	Output Capacitance		890			$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0MHz$
Coss	Output Capacitance		110			$V_{GS} = 0V$ , $V_{DS} = 44V$ , $f = 1.0MHz$
Coss eff.	Effective Output Capacitance ⑤		210			$V_{GS} = 0V$ , $V_{DS} = 0V$ to 44V

### **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			25		MOSFET symbol
	(Body Diode)			23	Α	showing the
I <sub>SM</sub>	Pulsed Source Current			100		integral reverse
	(Body Diode) ①					p-n junction diode.
V <sub>SD</sub>	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$ , $I_S = 15A$ , $V_{GS} = 0V$ ④
t <sub>rr</sub>	Reverse Recovery Time		52	78	ns	$T_J = 25^{\circ}C$ , $I_F = 15A$ , $V_{DD} = 28V$
Q <sub>rr</sub>	Reverse RecoveryCharge		82	120	nC	di/dt = 100A/μs ④
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )				

<sup>\*</sup> When mounted on 1" square PCB (FR-4 or G-10 Material) . For recommended footprint and soldering techniques refer to application note #AN-994 Notes ① through ® are on page 11

# International TOR Rectifier

## IRLR/U3105PbF

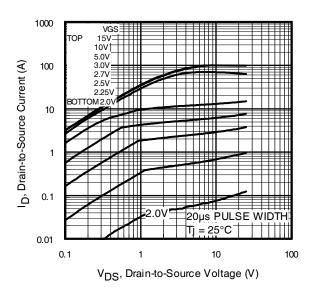


Fig 1. Typical Output Characteristics

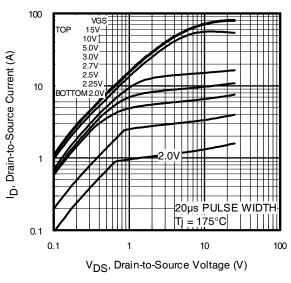


Fig 2. Typical Output Characteristics

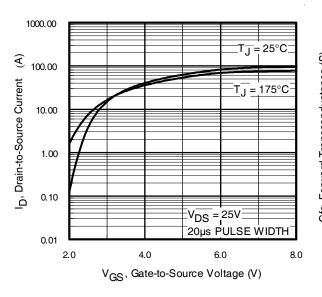


Fig 3. Typical Transfer Characteristics

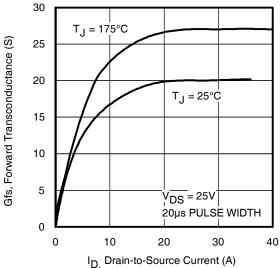
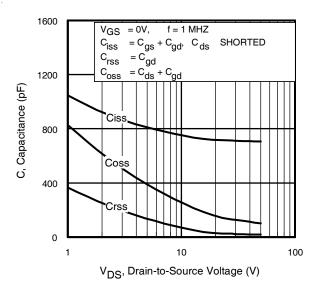
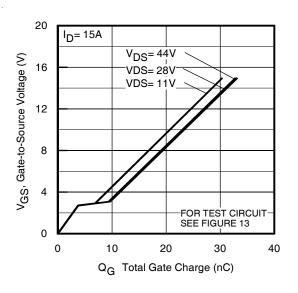


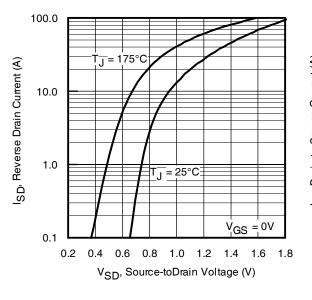
Fig 4. Typical Forward Transconductance Vs. Drain Current



**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage



**Fig 7.** Typical Source-Drain Diode Forward Voltage

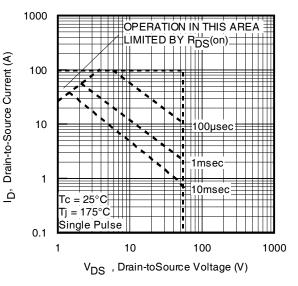
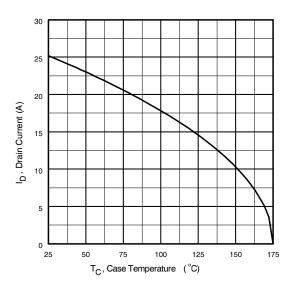


Fig 8. Maximum Safe Operating Area

# International TOR Rectifier

# IRLR/U3105PbF



I<sub>D</sub> = 25A 2.5 R<sub>DS(on)</sub>, Drain-to-Source On Resistance 2.0 (Normalized) 1.5 1.0 0.5 -60 120 140 160 180 0 20 40 60 80 ( ° C)  $T_J$ , Junction Temperature

**Fig 9.** Maximum Drain Current Vs. Case Temperature

**Fig 10.** Normalized On-Resistance Vs. Temperature

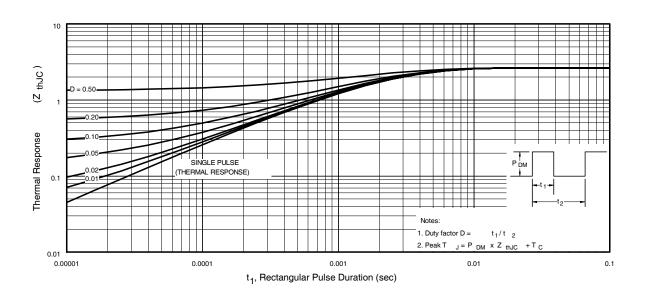


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

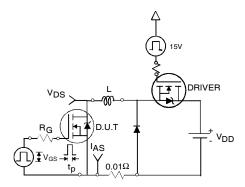


Fig 12a. Unclamped Inductive Test Circuit

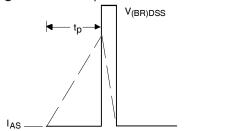


Fig 12b. | Unclamped Inductive Waveforms

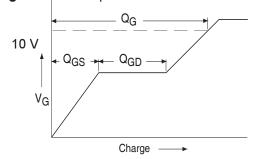
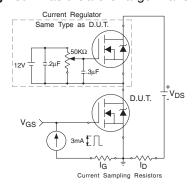
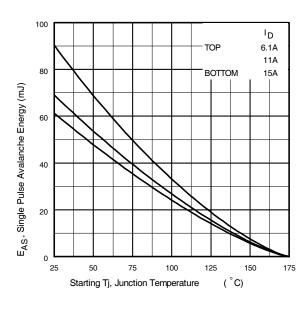


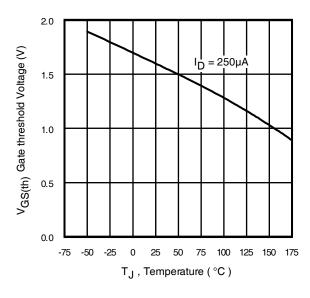
Fig 13a. Basic Gate Charge Waveform



**Fig 13b.** Gate Charge Test Circuit 6



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current



**Fig 14.** Threshold Voltage Vs. Temperature www.irf.com

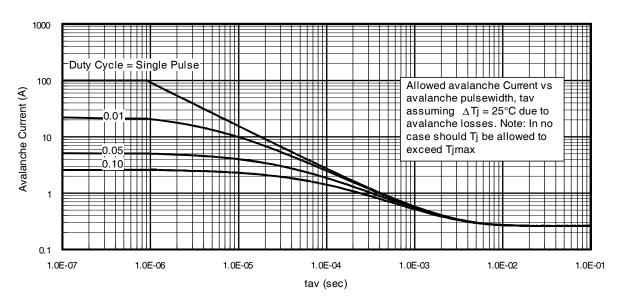
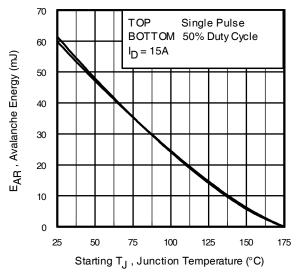


Fig 15. Typical Avalanche Current Vs. Pulsewidth



**Fig 16.** Maximum Avalanche Energy Vs. Temperature

## Notes on Repetitive Avalanche Curves, Figures 15, 16: (For further info, see AN-1005 at www.irf.com)

- Avalanche failures assumption: Purely a thermal phenomenon and failure occurs at a temperature far in excess of T<sub>jmax</sub>. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long  $asT_{jmax}$  is not exceeded.
- Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- P<sub>D (ave)</sub> = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I<sub>av</sub> = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 15, 16).  $t_{av}$  = Average time in avalanche.
  - D = Duty cycle in avalanche =  $t_{av} \cdot f$  $Z_{thJC}(D, t_{av})$  = Transient thermal resistance, see figure 11)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \triangle T / \; Z_{thJC} \\ I_{av} &= 2\triangle T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$

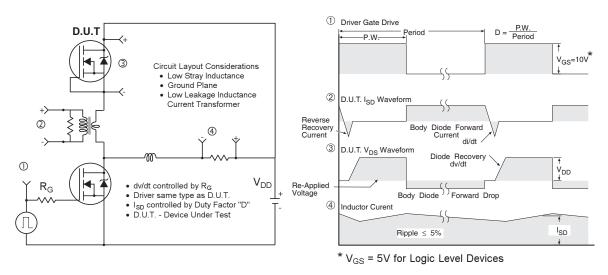


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

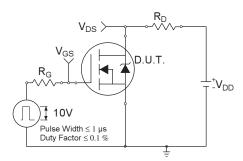


Fig 18a. Switching Time Test Circuit

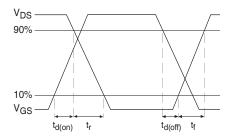


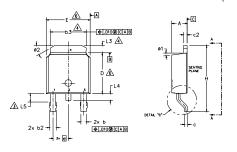
Fig 18b. Switching Time Waveforms

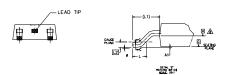
## International IOR Rectifier

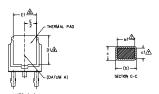
## IRLR/U3105PbF

## D-Pak (TO-252AA) Package Outline

Dimensions are shown in millimeters (inches)







- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].

  LEAD DIMENSION UNCONTROLLED IN L5.
- A- DIMENSION D1, E1, L3 & 63 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD.
- 5.— SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 AND 0.10 [0.13 AND 0.25] FROM THE LEAD TIP.
- DIMENSION D & E DO NOT INCLUDE MOLD FLASH. WOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.

- 9.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-252AA.

5 Y			SIONS			
й		Й				
B	MILLIM	ETERS	INCHES		O T E S	
B 0 L	MIN.	MAX.	MIN.	MAX.	E S	
Α	2,18	2.39	.086	.094		
A1	-	0.13	-	.005		
ь	0.64	0.89	.025	.035		
ь1	0.65	0.79	.025	.031	7	
b2	0.76	1,14	.030	.045		
b3	4,95	5.46	.195	.215	4	
С	0.46	0.61	.018	.024		
c1	0.41	0.56	.016	.022	7	
с2	0,46	0.89	.018	.035		
D	5.97	6.22	.235	.245	6	
D1	5.21	-	.205	-	4	
Ε	6.35	6.73	.250	.265	6	
E1	4.32	-	.170	-	4	
e	2,29	BSC	.090	090 BSC		
н	9,40	10,41	.370	,410		
L	1,40	1,78	.055	.070		
L1	2.74 BSC		.108			
L2	0.51 BSC		.020 BSC			
L3	0,89	1,27	.035	.050	4	
L4	-	1,02	-	.040		
L5	1,14	1.52	.045	.060	3	
ø	0.	10*	0,	10*		
ø1	0.	15*	0,	15*		
ø2	25*	35*	25*	35*		

#### LEAD ASSIGNMENTS

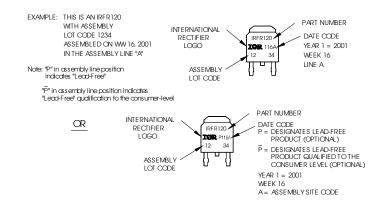
#### HEXFET

- 1.- GATE 2.- DRAIN 3.- SOURCE 4.- DRAIN

#### IGBT & CoPAK

- 1.- GATE 2.- COLLECTOR 3.- EMITTER 4.- COLLECTOR

## D-Pak (TO-252AA) Part Marking Information



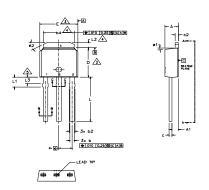
- 1. For an Automotive Qualified version of this part please seehttp://www.irf.com/product-info/auto/
- 2. For the most current drawing please refer to IR website at http://www.irf.com/package/

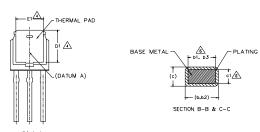
## IRLR/U3105PbF



## I-Pak (TO-251AA) Package Outline

Dimensions are shown in millimeters (inches)





- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- ⚠ DIMENSION D & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- A- THERMAL PAD CONTOUR OPTION WITHIN DIMENSION 64, L2, E1 & D1.
- A- LEAD DIMENSION UNCONTROLLED IN L3.
- ⚠- DIMENSION 61, 63 & c1 APPLY TO BASE METAL ONLY.
- 7.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-251AA (Date 06/02).
- 8.- CONTROLLING DIMENSION ; INCHES.

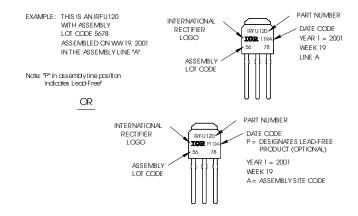
S Y DIMENSIONS						
B	MILLIMETERS		INC	Ŏ Ţ		
L	MIN, MAX.		MIN.	MAX,	Ė	
Α	2.18	2.39	.086	.094		
A1	0.89	1,14	.035	.045		
ь	0.64	0.89	.025	.035		
ь1	0.65	0.79	.025	.031	6	
b2	0.76	1,14	.030	.045		
ь3	0.76	1.04	.030	.041	6	
b4	4,95	5,46	.195	.215	4	
С	0.46	0.61	.018	.024		
c1	0,41	0.56	.016	.022	6	
c2	0.46	0.89	.018	.035		
D	5.97	6.22	.235	.245	3	
D1	5.21	-	.205	-	4	
Ε	6.35	6.73	.250	.265	3	
E1	4.32	-	.170	-	4	
е	2.29 BSC		.090 BSC		1	
L	8.89	9.65	.350	.380	1	
L1	1,91	2.29	.045	.090		
L2	0.89	1,27	.035	.050	4	
L3	1,14	1,52	.045	.060	5	
ø1	0.	15*	0.	15*		
02	25*	35*	25*	35*		

#### LEAD ASSIGNMENTS

#### HEXFET

- 1.- GATE 2.- DRAIN 3.- SOURCE 4.- DRAIN

## I-Pak (TO-251AA) Part Marking Information



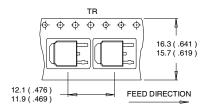
#### Notes:

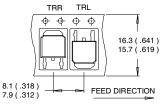
- 1. For an Automotive Qualified version of this part please seehttp://www.irf.com/product-info/auto/
- 2. For the most current drawing please refer to IR website at http://www.irf.com/package/

## IRLR/U3105PbF

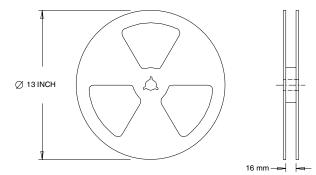
## D-Pak (TO-252AA) Tape & Reel Information

Dimensions are shown in millimeters (inches)





- 1. CONTROLLING DIMENSION : MILLIMETER.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
  3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES: 1. OUTLINE CONFORMS TO EIA-481.

### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- $\odot$  Limited by  $T_{Jmax}$ , starting  $T_J = 25$ °C, L = 0.55mH $R_G=25\Omega,\,I_{AS}=15A,\,V_{GS}=10V$
- $\label{eq:loss_def} \text{ } \text{ } \text{ } I_{SD} \leq 25\text{A}, \text{ } \text{di/dt} \leq 290\text{A/}\mu\text{s}, \text{ } V_{DD} \leq V_{(BR)DSS},$  $T_J \leq 175^{\circ}C$
- ⓐ Pulse width ≤ 300 $\mu$ s; duty cycle ≤ 2%.
- ⑤ Coss eff. is a fixed capacitance that gives the same charging time as  $C_{\text{oss}}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$  .
- Limited by T<sub>Jmax</sub> see Fig 12a, 12b, 15, 16 for typical repetitive avalanche performance.
- This value determined from sample failure population. 100% tested to this value in production.

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market. Qualification Standards can be found on IR's Web site.



IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105

TAC Fax: (310) 252-7903

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